## How to Write a Quality Technical Paper and Where to Publish within IEEE – Part 2

George Plosker

IEEE Client Services Manager

September 2015



## Prepare Step by step...

# Your research problem must contribute new and important knowledge to your field

- Conduct a Literature Review
- Take Notes & Keep Track
- Gather References & Citations
- Draft an Outline





## **Tools to start your literature** review

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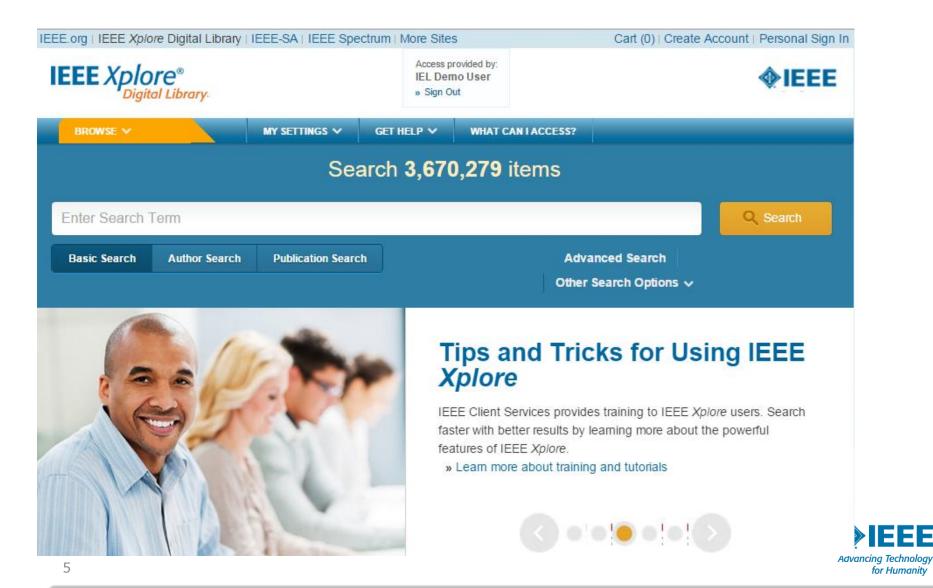


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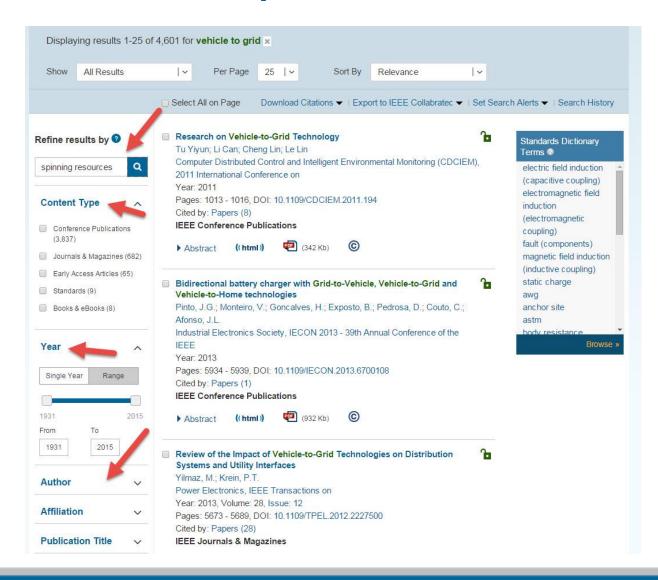


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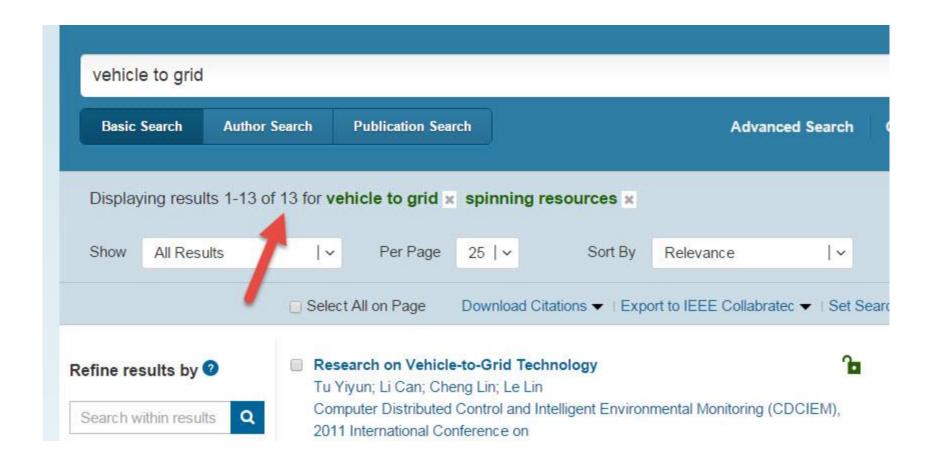


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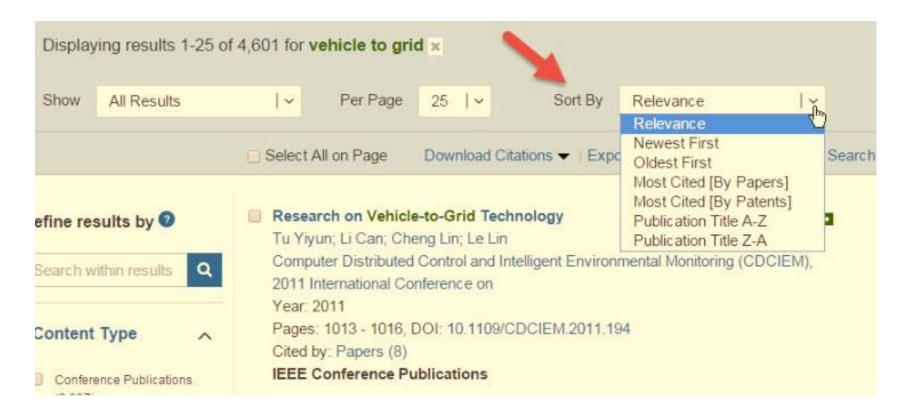


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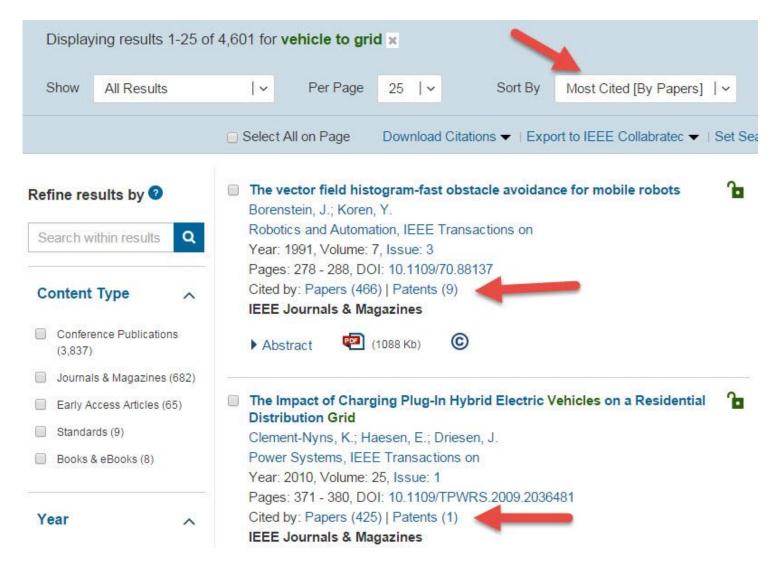


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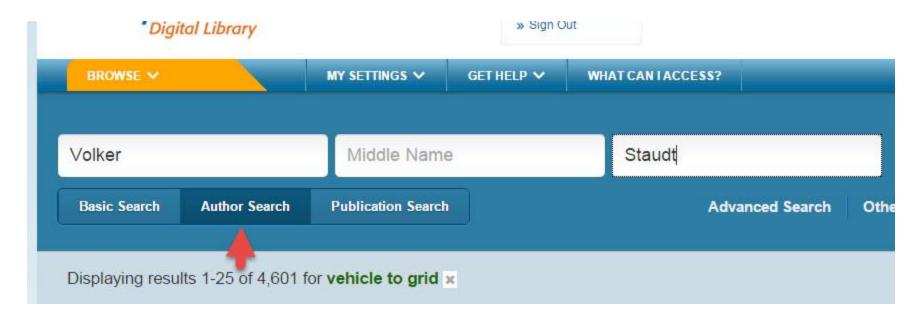


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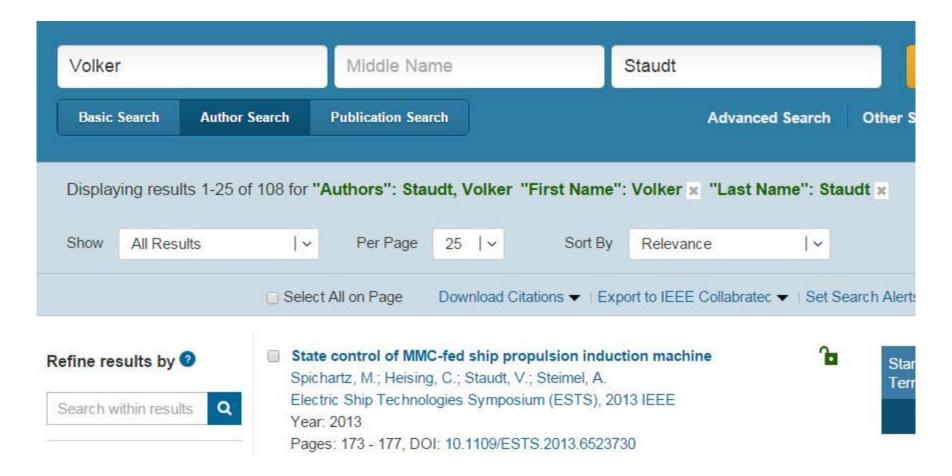


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## Or filter keyword searches



Review of the Impact of Vehicle-to-Grid Technologies on Distribution Systems and Utility Interfaces

Yilmaz, M.; Krein, P.T.

Power Electronics, IEEE Transactions on

Year: 2013, Volume: 28, Issue: 12

Pages: 5673 - 5689, DOI: 10.1109/TPEL.2012.2227500

Cited by: Papers (28)

IEEE Journals & Magazines

Abstract

((html))



(838 Kb)



Modeling the Benefits of Vehicle-to-Grid Technology to a Power System

Yuchao Ma; Houghton, T.; Cruden, A.; Infield, D.

Power Systems, IEEE Transactions on

Year: 2012, Volume: 27, Issue: 2

Pages: 1012 - 1020, DOI: 10.1109/TPWRS.2011.2178043



## Prepare Step by step...

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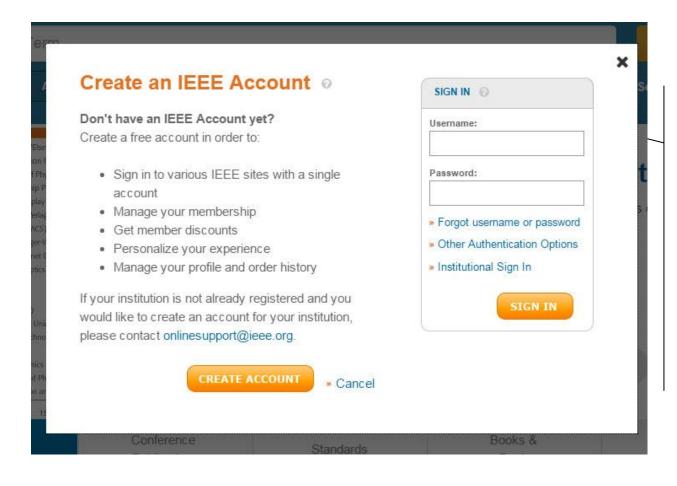
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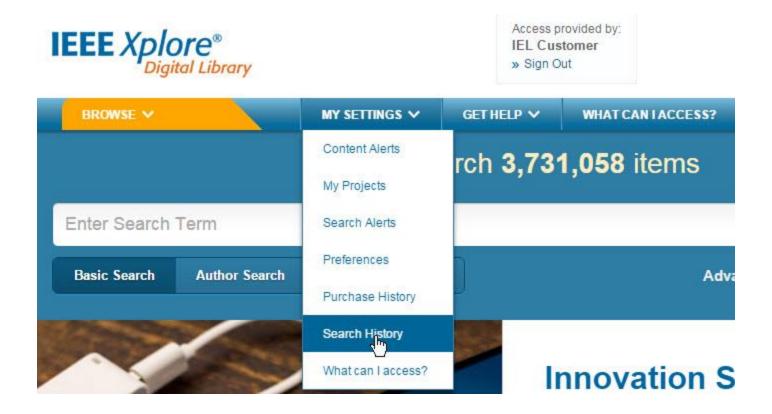
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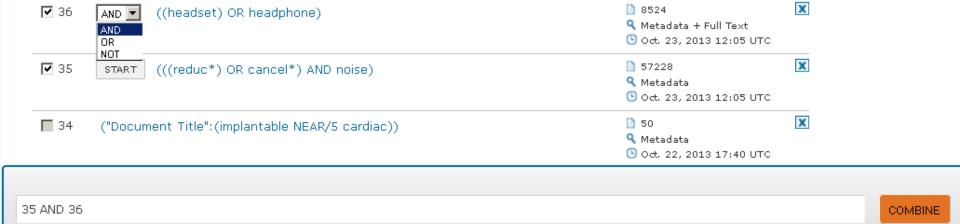
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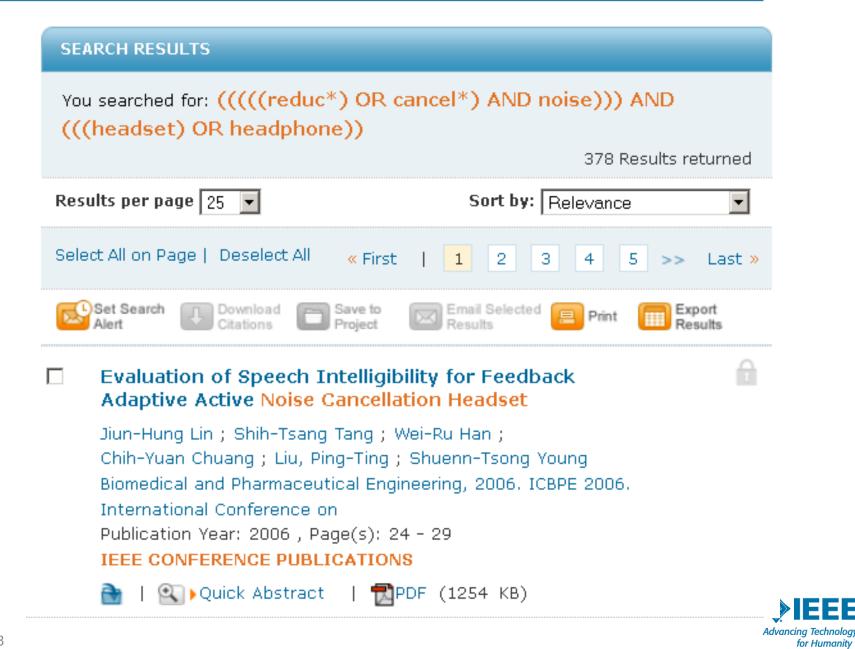
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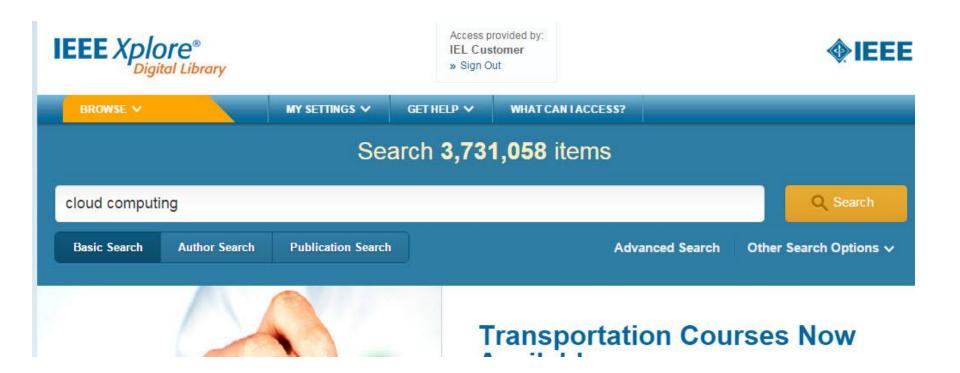
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(((PLL) OR "phase locked loop") AND synthesiz\*)



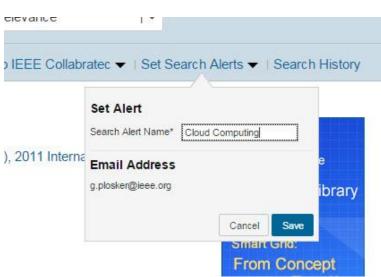
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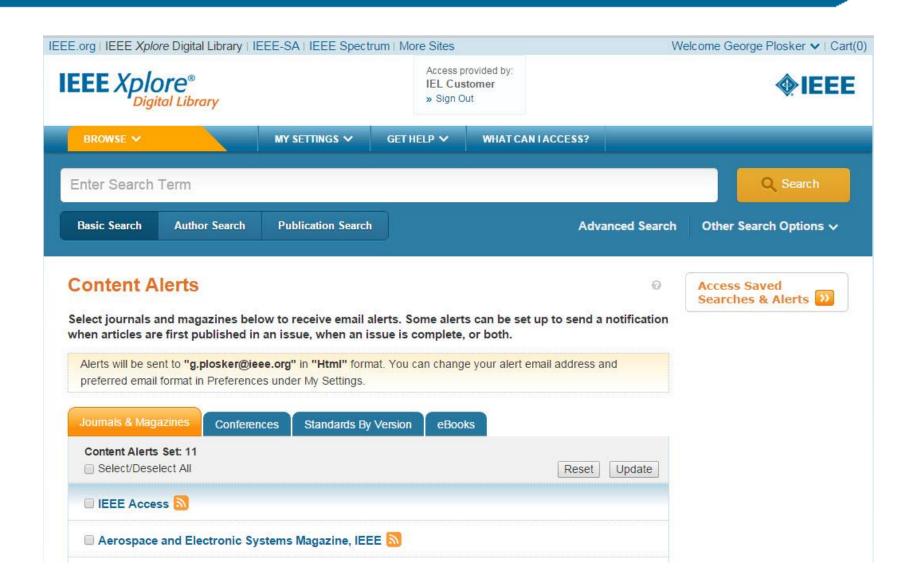
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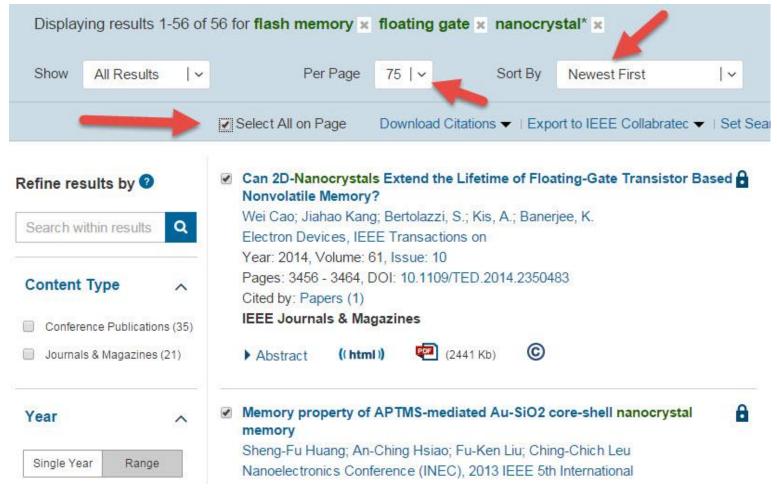


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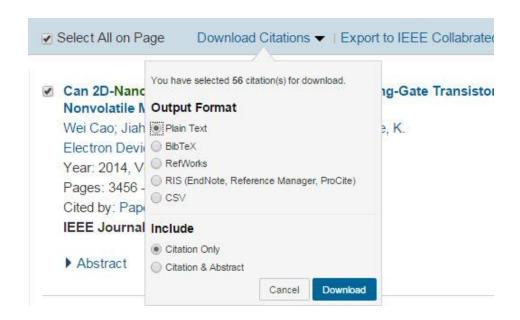
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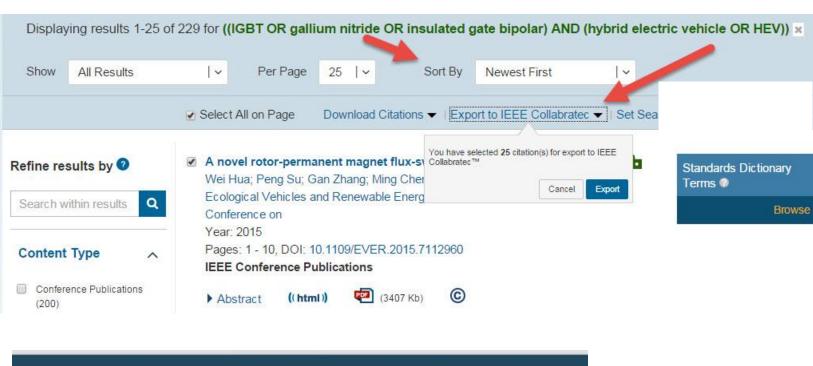
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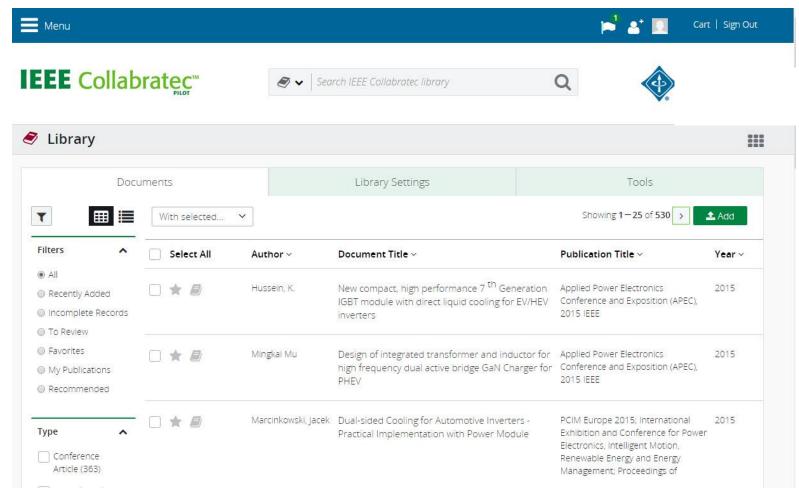
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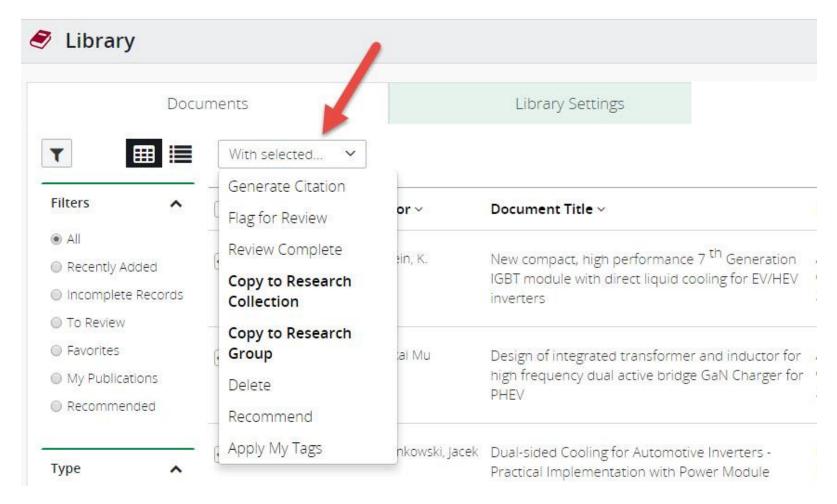


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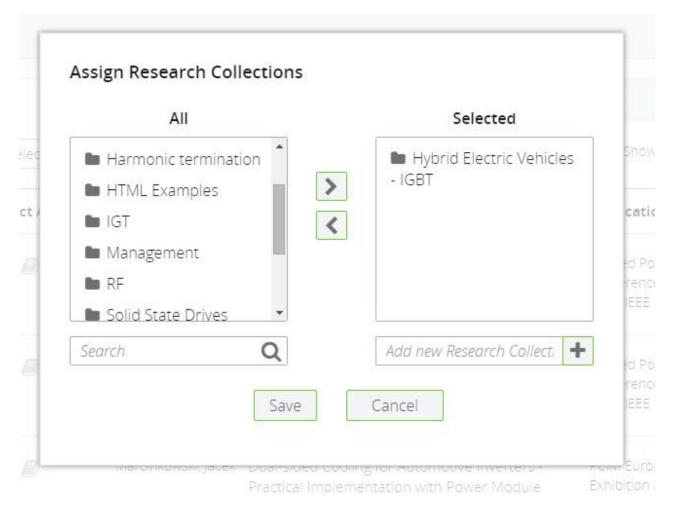






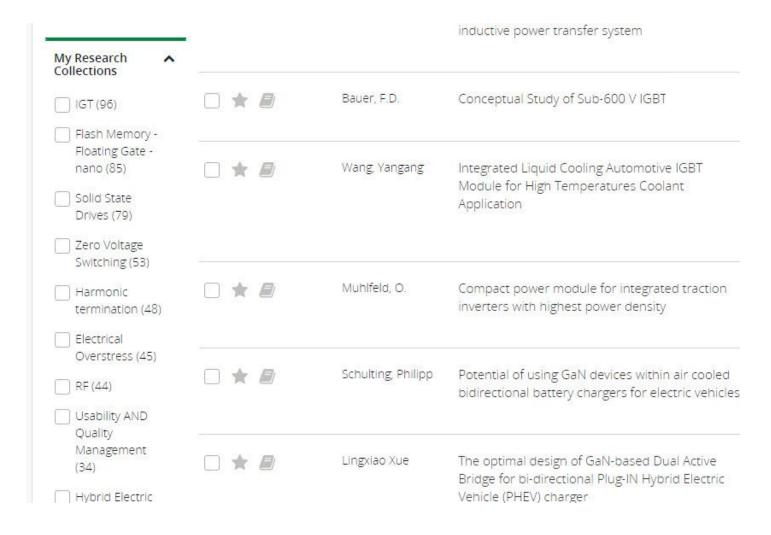


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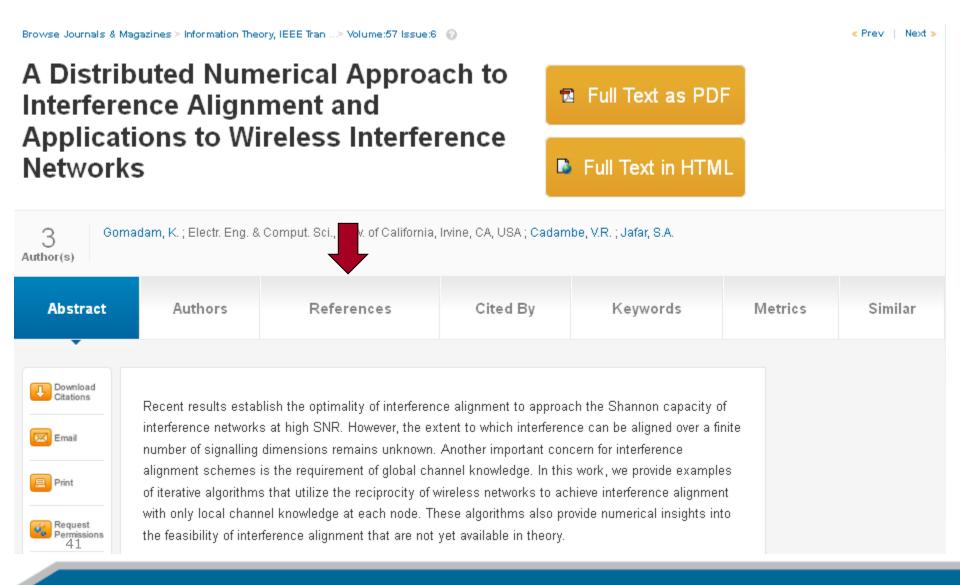


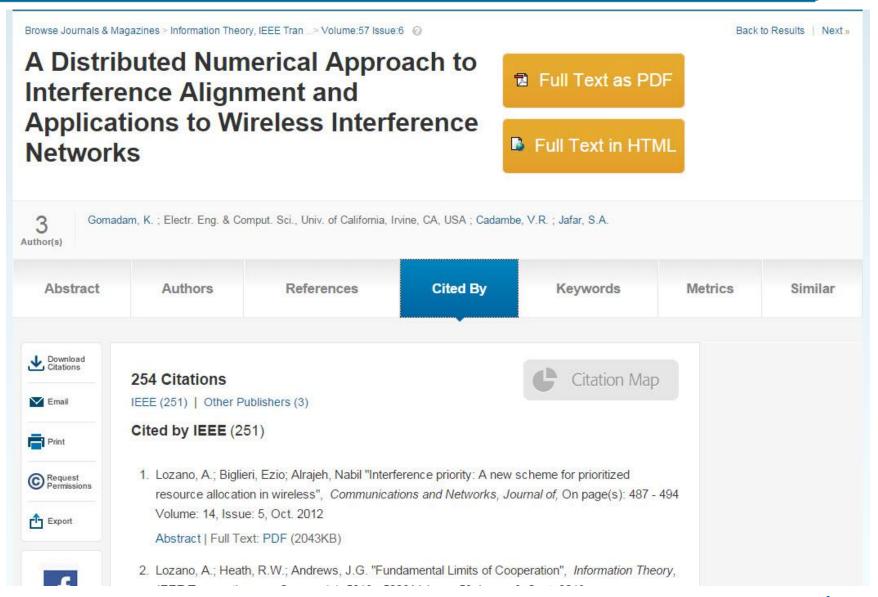
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#### Cited by Patents (1)

 Pereira, Stephanie F.; Xue, Feng, "WIRELESS NETWORK AND METHOD FOR ADAPTIVE OPPORTUNISTIC CLUSTERING FOR INTERFERENCE ALIGNMENT IN WIRELESS NETWORKS" , Patent No. 8036098

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#### Inventors:

Pereira, Stephanie F.; Xue, Feng

#### Abstract:

Embodiments Of A Central Scheduler And Method For Adaptive Clustering Are Generally Described Herein. In Some Embodiments, A Cluster Of Transmitter-receiver Pairs Is Selected Based On Minimum Singular Values Calculated From Direct Channel Information And The Selected Pairs Are Instructed To Perform An Interference Alignment Technique. </P>

#### Assignee:

INTEL CORP

#### Filing Date:

April 20, 2009

#### **Grant Date:**

October 11, 2011

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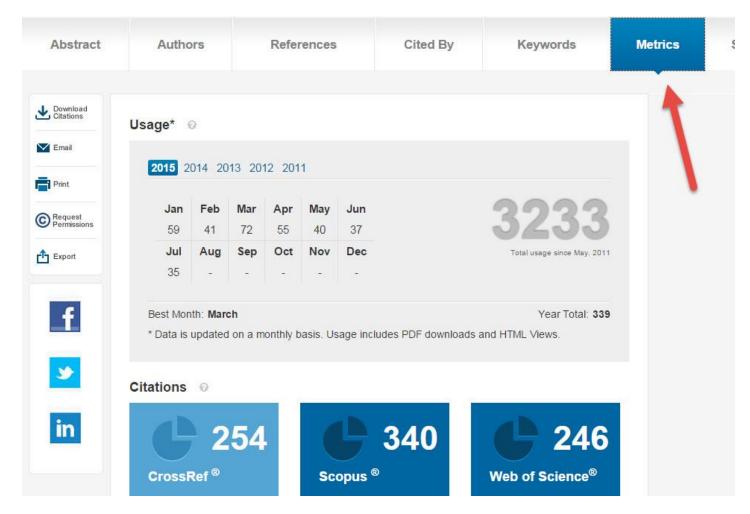
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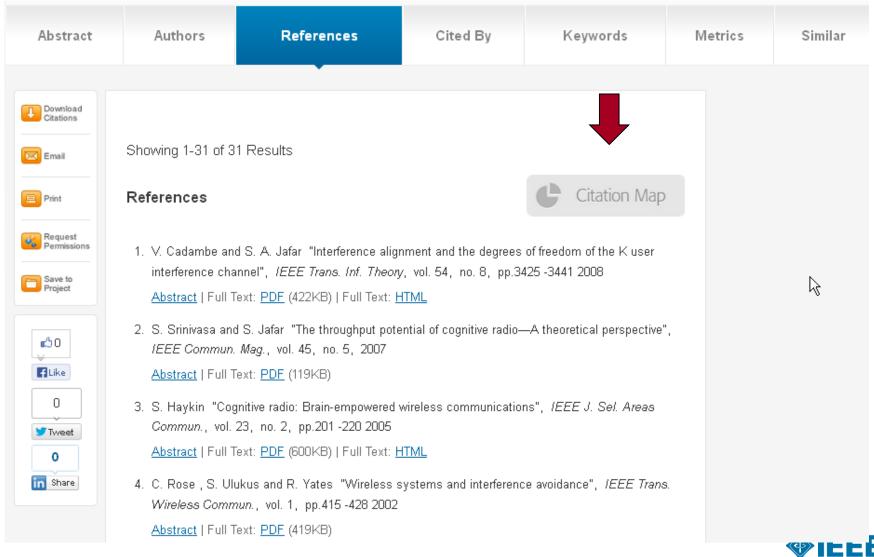


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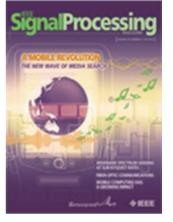
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The theory, design and application of Control Systems. It shall encompass components, and the integration of these components, as are necessary for the construction of such systems. The word 'systems' as used herein shall be interpreted to include physical, biological, organizational and other entities and combinations thereof, which can be represented through a mathematical symbolism. The Field of Interest: shall include scientific, technical, industrial or other activities that contribute to this field, or utilize the techniques or products of this field, subject, as the art develops, to additions, subtractions, or other modifications directed or approved by the IEEE Technical Activities Board.

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 ( 1956 - 1962 ) Automatic Control, IRE Transactions on

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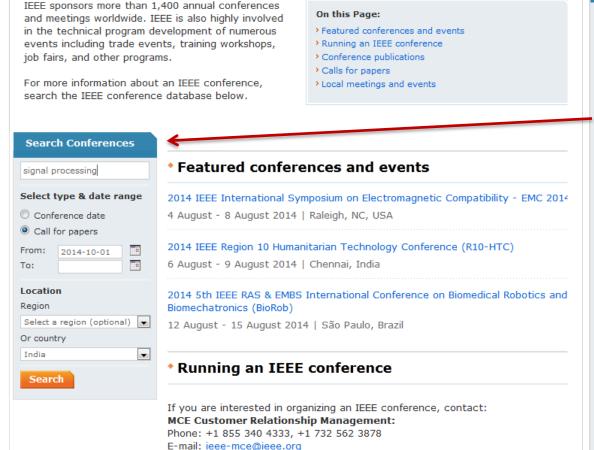
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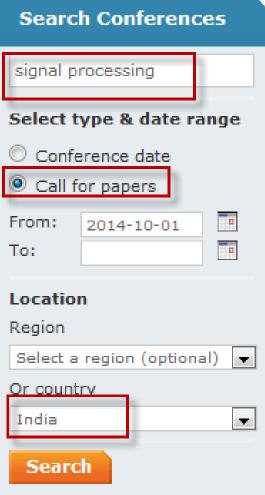




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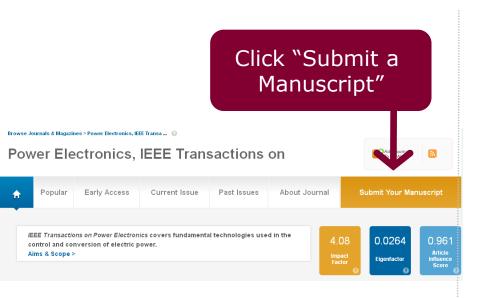


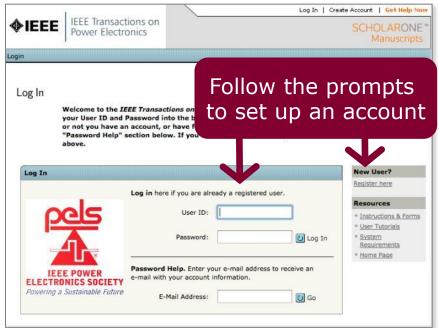




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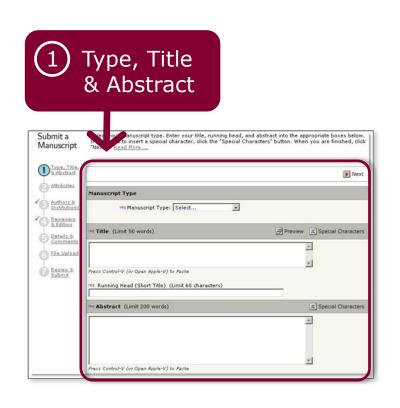


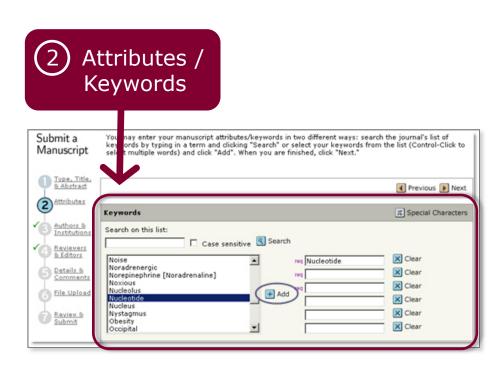




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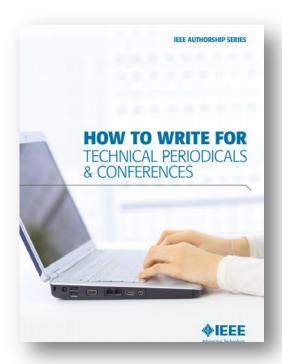
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